

**Search Notes**

Application/Control No.

10/560,672

Examiner

Karen Cheng

Applicant(s)/Patent under  
Reexamination

BAYLY ET AL.

Art Unit

1626

**SEARCHED**

Class	Subclass	Date	Examiner
514	329	7/20/2007	KC
514	398	7/20/2007	KC
546	192	7/20/2007	KC
546	330	7/20/2007	KC
548	335.1	7/20/2007	KC

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
STN Structure Search (see attached)	7/11/2007	KC
Inventor Name Search (EDan)	7/12/2007	KC
EAST Search (see attached)	7/20/2007	KC